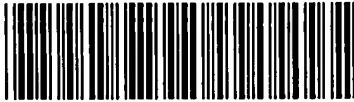


**Search Notes**

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Examiner

Tan V. Mai

Applicant(s)/Patent under  
Reexamination

ZHENG ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
708	550-553	11/7/2007	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	11/7/2007	MAI